

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination GAUTHIER ET AL.	
		10/075,750	Examiner	Art Unit Cassandra Cox

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-6,441,602	08-2002	Eckhardt et al.	324/76.53
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**NON-PATENT DOCUMENTS**

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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.